IGBT - Field Stop, IV/4 Lead

FGH75T65SQDNL4

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop IV Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss. In addition, this new device is packaged in a TO–247–4L package that provides significant reduction in E_{on} Losses compared to standard TO–247–3L package. The IGBT is well suited for UPS and solar applications. Incorporated into the device is a soft and fast co–packaged free wheeling diode with a low forward voltage.

Features

- Extremely Efficient Trench with Field Stop Technology
- $T_{Jmax} = 175^{\circ}C$
- Improved Gate Control Lowers Switching Losses
- Separate Emitter Drive Pin
- TO-247-4L for Minimal E_{on} Losses
- Optimized for High Speed Switching
- 100% of the Parts Tested for I_{LM}
- These are Pb-Free Devices

Typical Applications

- Solar Inverter
- Uninterruptible Power Inverter Supplies (UPS)
- Neutral Point Clamp Topology

ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-emitter voltage	V _{CES}	650	V
Collector current @ Tc = 25°C @ Tc = 100°C	I _C	150 75	A
Diode Forward Current @ Tc = 25°C @ Tc = 100°C	l _F	150 75	A
Diode Pulsed Current T _{PULSE} Limited by T _J Max	I _{FM}	300	Α
Pulsed collector current, T _{pulse} limited by T _{Jmax}	I _{CM} I _{LM}	300	Α
Gate-emitter voltage	V_{GE}	±20	V
Transient gate-emitter voltage ($T_{PULSE} = 5 \mu s$, D < 0.10)		±30	V
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P _D	375 188	W
Operating junction temperature range	T_J	-55 to +175	°C
Storage temperature range	T _{stg}	-55 to +175	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T _{SLD}	260	°C

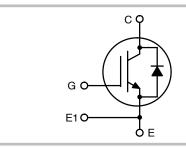
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

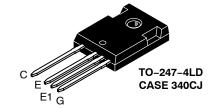


ON Semiconductor®

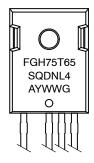
www.onsemi.com

75 A, 650 V V_{CEsat} (Typ.) = 1.6 V





MARKING DIAGRAM



A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping
FGH75T65SQDNL4	TO-247 (Pb-Free)	30 Units / Rail

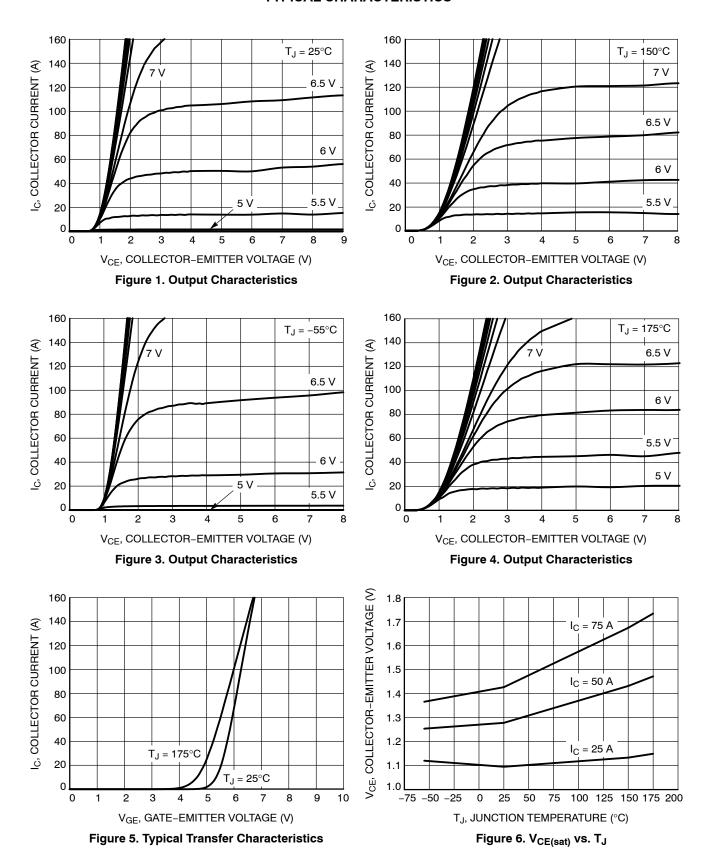
THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.4	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ heta JC}$	0.65	°C/W
Thermal resistance junction-to-ambient	$R_{ hetaJA}$	40	°C/W

ELECTRICAL CHARACTERISTICS ($T_J = 25$ °C unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC					•	
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0 \text{ V, I}_{C} = 500 \mu\text{A}$	V _{(BR)CES}	650	_	_	V
Collector-emitter saturation voltage	V _{GE} = 15 V, I _C = 75 A V _{GE} = 15 V, I _C = 75 A, T _J = 175°C	V _{CEsat}	-	1.6 1.92	2.1 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}$, $I_C = 75 \text{ mA}$	V _{GE(th)}	4.0	4.8	5.6	V
Collector-emitter cut-off current, gate- emitter short-circuited	$V_{GE} = 0 \text{ V}, V_{CE} = 650 \text{ V}$ $V_{GE} = 0 \text{ V}, V_{CE} = 650 \text{ V}, T_{J=175^{\circ}\text{C}}$	I _{CES}	- -	- 6.0	0.25 -	mA
Gate leakage current, collector-emitter short-circuited	V _{GE} = 20 V , V _{CE} = 0 V	I _{GES}	-	-	±250	nA
DYNAMIC CHARACTERISTIC						
Input capacitance		C _{ies}	_	5100	_	pF
Output capacitance	V _{CE} = 30 V, V _{GE} = 0 V, f = 1 MHz	C _{oes}	-	115	-	
Reverse transfer capacitance	1	C _{res}	-	12	-	
Gate charge total		Qg	-	152	-	nC
Gate to emitter charge	V _{CE} = 400 V, I _C = 75 A, V _{GE} = 15 V	Q _{ge}	_	29	-	
Gate to collector charge	1	Q _{gc}	-	39	-	
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD				•	
Turn-on delay time		t _{d(on)}	-	59	_	ns
Rise time	1	t _r	_	58	-	
Turn-off delay time	T _J = 25°C	t _{d(off)}	_	354	-	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 75 \text{ A}$ $R_{q} = 20 \Omega$	t _f	_	69	-	
Turn-on switching loss	V _{GE} = 15 V	E _{on}	-	1.82	-	mJ
Turn-off switching loss	1	E _{off}	-	1.86	-	
Total switching loss	1	E _{ts}	-	3.68	-	
Turn-on delay time		t _{d(on)}	_	56	-	ns
Rise time	1	t _r	_	57	-	
Turn-off delay time	T _J = 175°C	t _{d(off)}	_	394	-	
Fall time	$V_{CC} = 400 \text{ V}, I_C = 75 \text{ A}$	t _f	-	73	-	
Turn-on switching loss	$R_g = 20 \Omega$ $V_{GE} = 15 V$	E _{on}	-	2.22	-	mJ
Turn-off switching loss	1	E _{off}	-	2.02	-	
Total switching loss	1	E _{ts}	-	4.24	-	
DIODE CHARACTERISTIC						
Forward voltage	$V_{GE} = 0 \text{ V, } I_F = 75 \text{ A}$ $V_{GE} = 0 \text{ V, } I_F = 75 \text{ A, } T_J = 175^{\circ}\text{C}$	V _F	- -	1.60 1.70	2.0 -	V
Reverse recovery time	T _{.1} = 25°C	t _{rr}	-	134	-	ns
Reverse recovery charge	$I_F = 75 \text{ Å}, V_R = 200 \text{ V}$	Q _{rr}	-	0.78	-	μC
Reverse recovery current	di _F /dt = 200 A/μs	I _{rrm}	-	10	_	Α
Reverse recovery time	T _J = 175°C	t _{rr}	-	202	_	ns
Reverse recovery charge	$I_F = 75 \text{ A}, V_R = 200 \text{ V}$	Q _{rr}	-	2.54	_	μC
Reverse recovery current	di _F /dt = 200 A/μs	I _{rrm}	_	20.2	-	Α

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



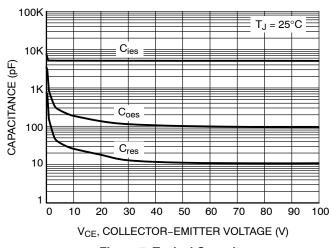


Figure 7. Typical Capacitance

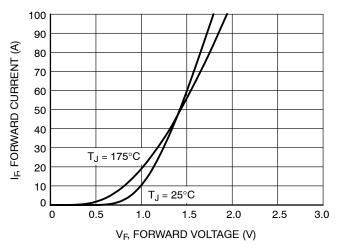


Figure 8. Diode Forward Characteristics

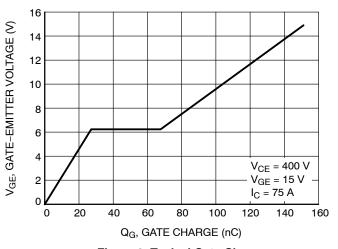


Figure 9. Typical Gate Charge

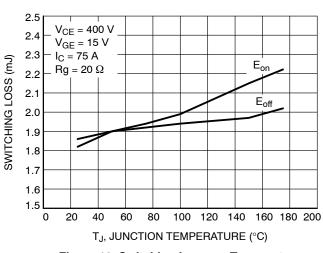


Figure 10. Switching Loss vs. Temperature

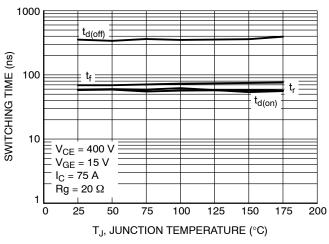


Figure 11. Switching Time vs. Temperature

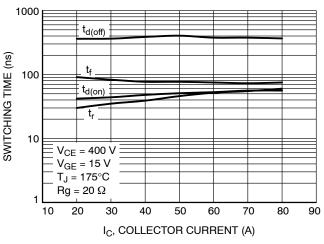


Figure 12. Switching Time vs. IC

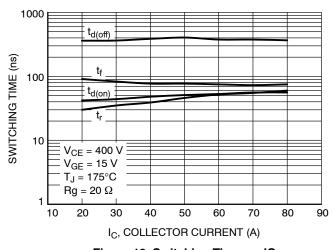


Figure 13. Switching Time vs. IC

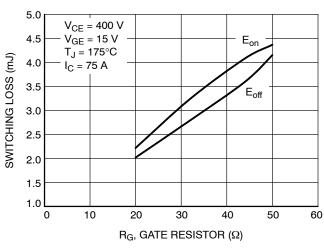


Figure 14. Switching Loss vs. R_G

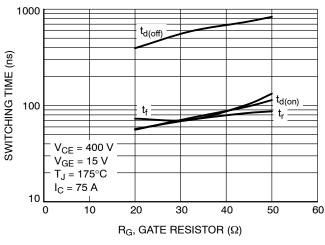


Figure 15. Switching Time vs. R_G

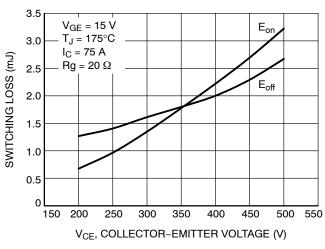


Figure 16. Switching Loss vs. V_{CE}

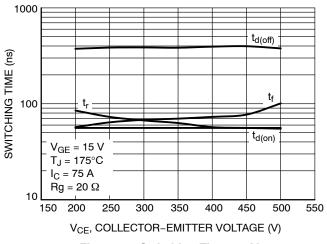


Figure 17. Switching Time vs. V_{CE}

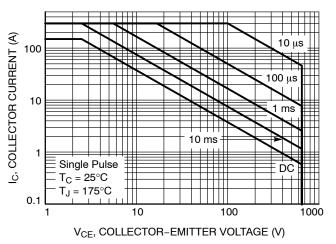
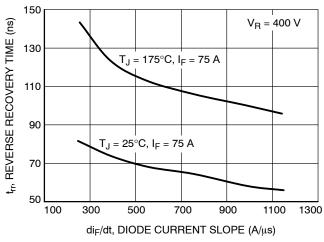


Figure 18. Safe Operating Area



 Q_{rr} REVERSE RECOVERY CHARGE (μC) 3.0 V_R = 400 V 2.5 2.0 $T_J = 175^{\circ}C$, $I_F = 75 A$ 1.5 $T_J = 25^{\circ}C, I_F = 75 A$ 1.0 0.5 0 100 300 500 700 900 1100 1300 di_F/dt , DIODE CURRENT SLOPE (A/ μ s)

Figure 19. t_{rr} vs. di_F/dt

Figure 20. Q_{rr} vs. di_F/dt

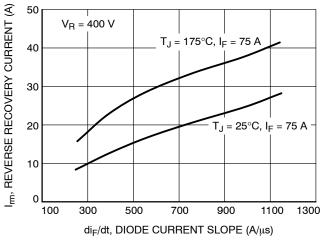


Figure 21. I_{rm} vs. di_F/dt

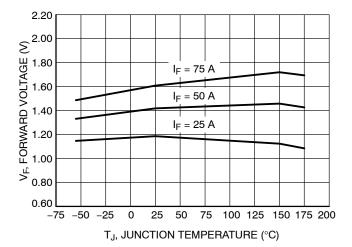


Figure 22. V_F vs. T_J

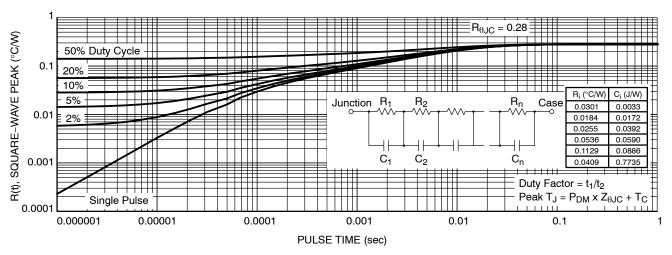


Figure 23. IGBT Transient Thermal Impedance

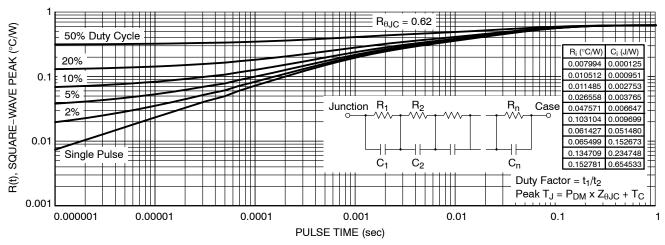


Figure 24. Diode Transient Thermal Impedance

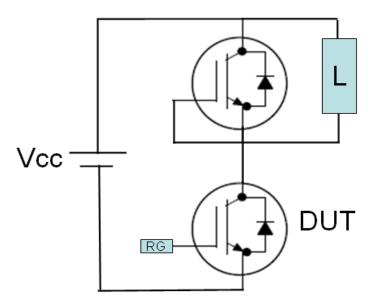


Figure 25. Test Circuit for Switching Characteristics

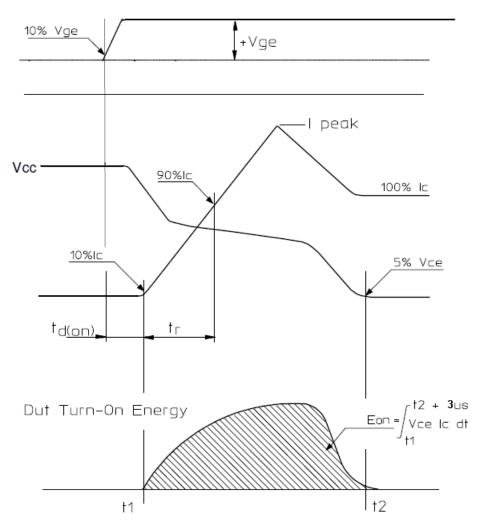


Figure 26. Definition of Turn On Waveform

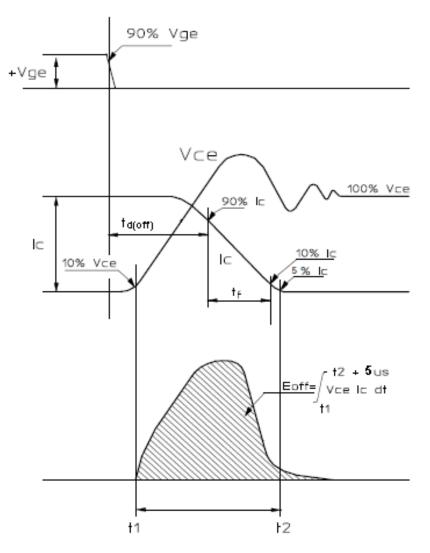
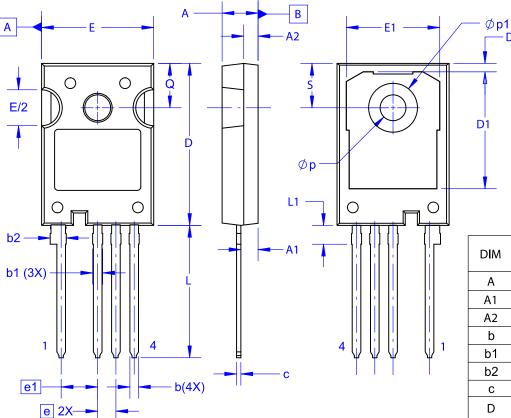


Figure 27. Definition of Turn Off Waveform

TO-247-4LD CASE 340CJ **ISSUE A**

DATE 16 SEP 2019

D2



NOTES:

0.254 M

- A. NO INDUSTRY STANDARD APPLIES TO THIS PACKAGE.
 B. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD
 FLASH, AND TIE BAR EXTRUSIONS.
 C. ALL DIMENSIONS ARE IN MILLIMETERS.

C. ALL DIMENSIONS ARE IN MILLIMETERS.
D. DRAWING CONFORMS TO ASME Y14.5-2009.

DIM	WILLINIETEKS			
DIM	MIN	NOM	MAX	
Α	4.80	5.00	5.20	
A1	2.10	2.40	2.70	
A2	1.80	2.00	2.20	
b	1.07	1.20	1.33	
b1	1.20	1.40	1.60	
b2	2.02	2.22	2.42	
С	0.50	0.60	0.70	
D	22.34	22.54	22.74	
D1	16.00	16.25	16.50	
D2	0.97	1.17	1.37	
е	2.54 BSC			
e1	5.08 BSC			
E	15.40	15.60	15.80	
E1	12.80	13.00	13.20	
E/2	4.80	5.00	5.20	
L	18.22	18.42	18.62	
L1	2.42	2.62	2.82	
р	3.40	3.60	3.80	
p1	6.60	6.80	7.00	
Q	5.97	6.17	6.37	
S	5.97	6.17	6.37	

MILLIMETERS

DOCUMENT NUMBER:	98AON13852G	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	TO-247-4LD		PAGE 1 OF 1	

ON Semiconductor and (III) are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMI, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer pu

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

onsemi Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative